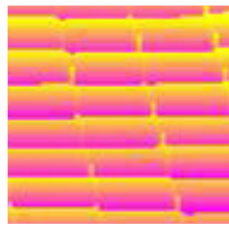
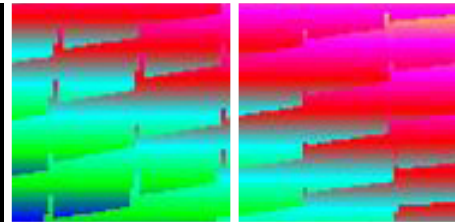




## Automated Silicon Stress Analysis



For industrial, research and quality testing applications microcrystalline Si

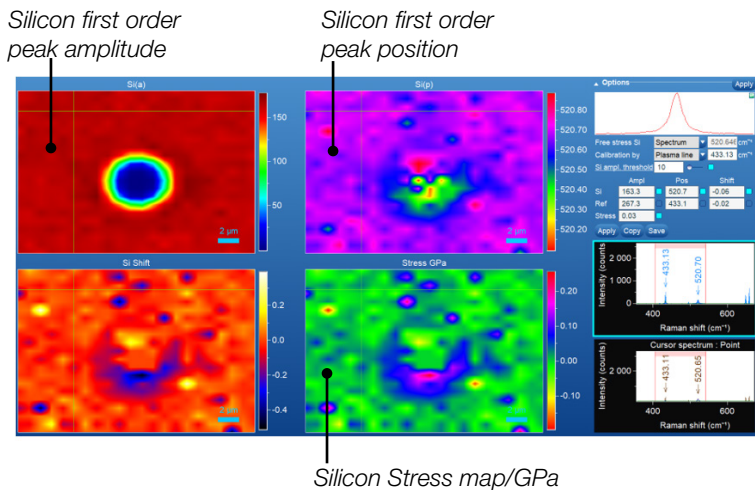


Embedded automated stress analysis of microcrystalline Silicon with optimized analysis reports

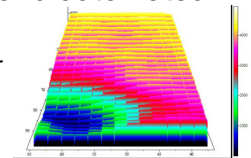
Raman Spectroscopy is one of the most important tools for investigating the basic properties of semiconductors. It is particularly effective at establishing the characteristics of photovoltaic cells and microelectronic devices.

Mechanical Stress and strain can be detected by analyzing the spectral shift of the band position. Allowing tensile and compressive strains to be quantified.

The **Si Stress App** joins the LabSpec6 Software Suite and provides rapid and reliable analysis in one click!



- Automatic Si Stress identification and qualification: tensile and compressive
- Integrated reference and automated data correction using Sample-Ref for very low level stress measurements
- Single point data and large mapping data set
- Optimized Analysis Report template



[info.sci@horiba.com](mailto:info.sci@horiba.com)

[www.horiba.com/scientific](http://www.horiba.com/scientific)